

Supporting information

Supplementary information for Dissolvable templates to prepare Pt-based porous metallic glass for oxygen reduction reaction

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Supporting Notes1: Calculation of electron transfer number (n)

The electron transfer number (n) is calculated by the Koutecky-Levich equation at various electrode potentials.

$$\frac{1}{i} = \frac{1}{i_k} + \frac{1}{i_d} = \frac{1}{nFA\kappa C_{O_2}} + \frac{1}{B\omega^{1/2}}$$
$$B = 0.2nFAC_{O_2}D_{O_2}^{2/3}V^{-1/6}$$

where i , i_k and i_d represent measured, kinetic and diffusion-limiting current, respectively, n represents the transferred electron number per oxygen molecule. F is faraday constant (96485 C mol^{-1}). A is the geometric electrode area (0.196 cm^2); κ is the rate constant for ORR (m s^{-1}); C_{O_2} is the saturated concentration of oxygen in 0.1 M KOH solution ($1.2 \times 10^{-6} \text{ mol cm}^{-3}$); D_{O_2} is the diffusion coefficient of oxygen in 0.1 M KOH solution ($1.9 \times 10^{-5} \text{ cm}^2 \text{ s}^{-1}$); V is the kinematic viscosity of solution ($0.01 \text{ cm}^2 \text{ s}^{-1}$); and ω is the angular rotation speed (rad s^{-1}). The constant 0.2 is adopted when the rotation speed is expressed in rpm.

Supplementary Note 2: Electrochemical characterization of the intrinsic activities of catalysts toward ORR

Electrochemical double-layer capacitance measurements were used to determine the electrochemically active surface areas (ECSA) of the electrocatalysts. The ECSA value was calculated based on the equation of $\text{ECSA} = C_{dl}/C_s$, where C_{dl} is the electrochemical double-layer capacitance and C_s is the specific capacitance. The C_s for a flat surface was generally found to be in the range of 20 to 60 $\mu\text{F cm}^{-2}$. In this work, we used a value of 20 $\mu\text{F cm}^{-2}$. For this, the potential window of cyclic voltammetric stripping was 1.07 V to 1.12 V versus RHE (0.1 M KOH solution). The scan rates were 3 mV s^{-1} , 5 mV s^{-1} , 10 mV s^{-1} , 20 mV s^{-1} , 40 mV s^{-1} , 50 mV s^{-1} , 60 mV s^{-1} , 80 mV s^{-1} and 100 mV s^{-1} . The C_{dl} was estimated by plotting the $\Delta j = (j_a - j_c)$ at 1.09 V (where j_c and j_a are the cathodic and anodic current densities, respectively) versus RHE against the scan rate, in which the slope was twice that of C_{dl} .

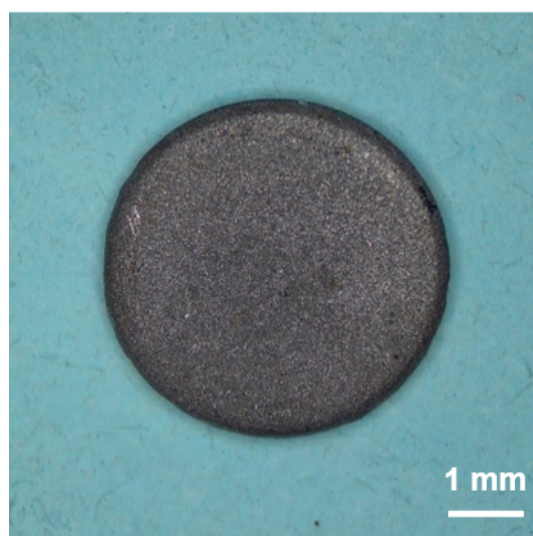


Fig. S1 The amorphous samples after hot pressing.

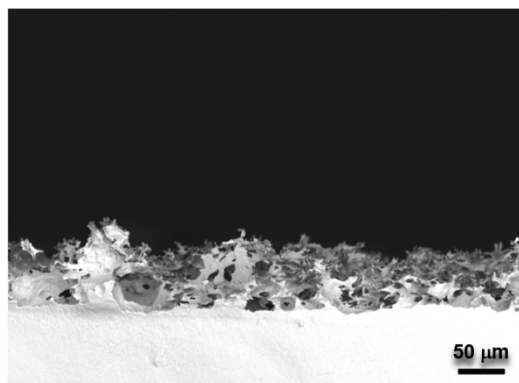


Fig. S2 The scanning electron microscope (SEM) section image of NPMG.

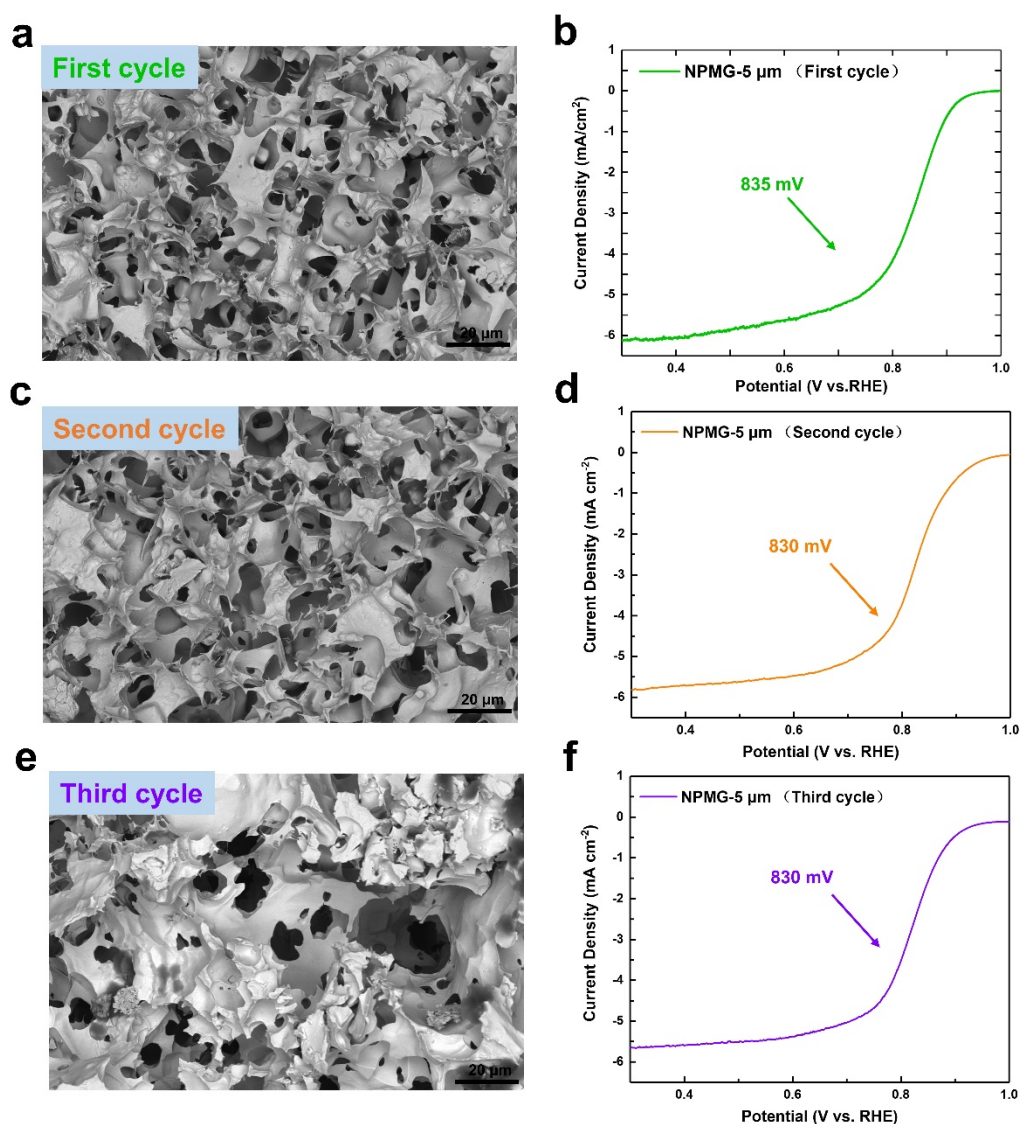


Fig. S3 (a) The surface morphology of NPMGs fabricated in the first cycle; (b) The half-wave potential of NPMGs fabricated in the first cycle; (c) The surface morphology of NPMGs fabricated in the second cycle; (d) The half-wave potential of NPMGs fabricated in the second cycle; (e) The surface morphology of NPMGs fabricated in the third cycle; (f) The half-wave potential of NPMGs fabricated in the third cycle.

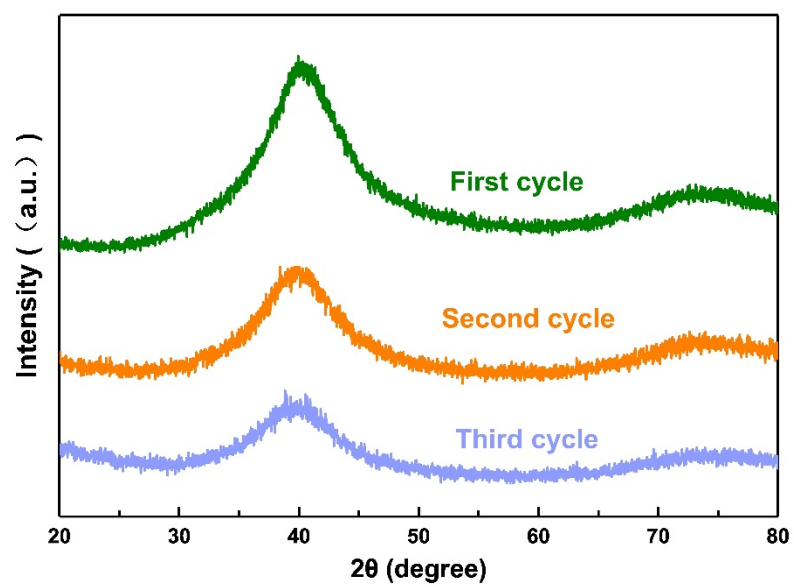


Fig. S4 The XRD pattern of original MG and reconstructed NPMGs.

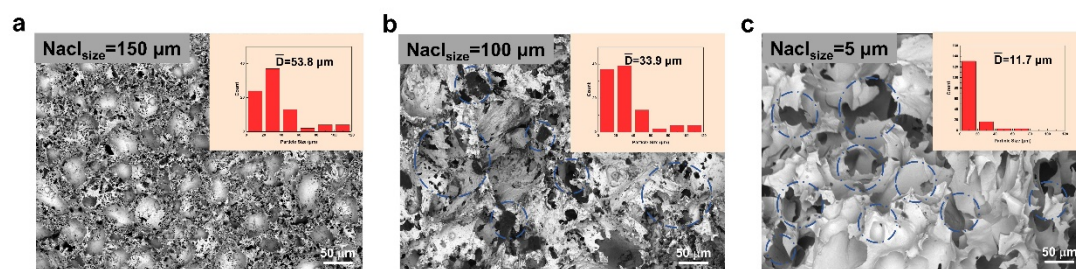


Fig. S5 The SEM of average pore size matched the size of the salt particles.

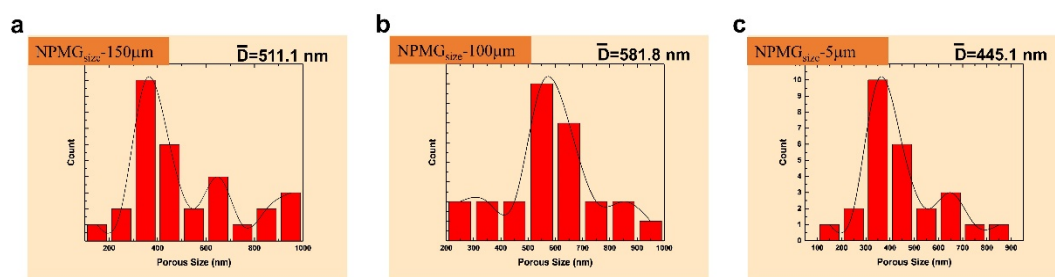


Fig. S6 The SEM of average nanopore size of NPMG-150 μ m, NPMG-100 μ m and NPMG-5 μ m.

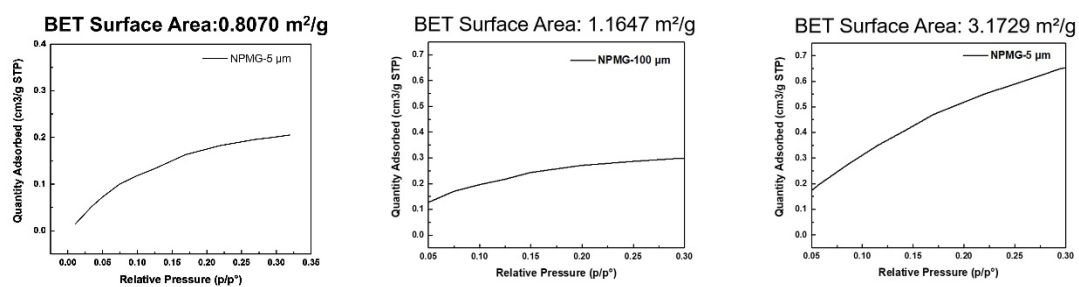


Fig. S7 Nitrogen adsorption curves (BET) for NPMG-150 μm , NPMG-100 μm and NPMG-5 μm samples.

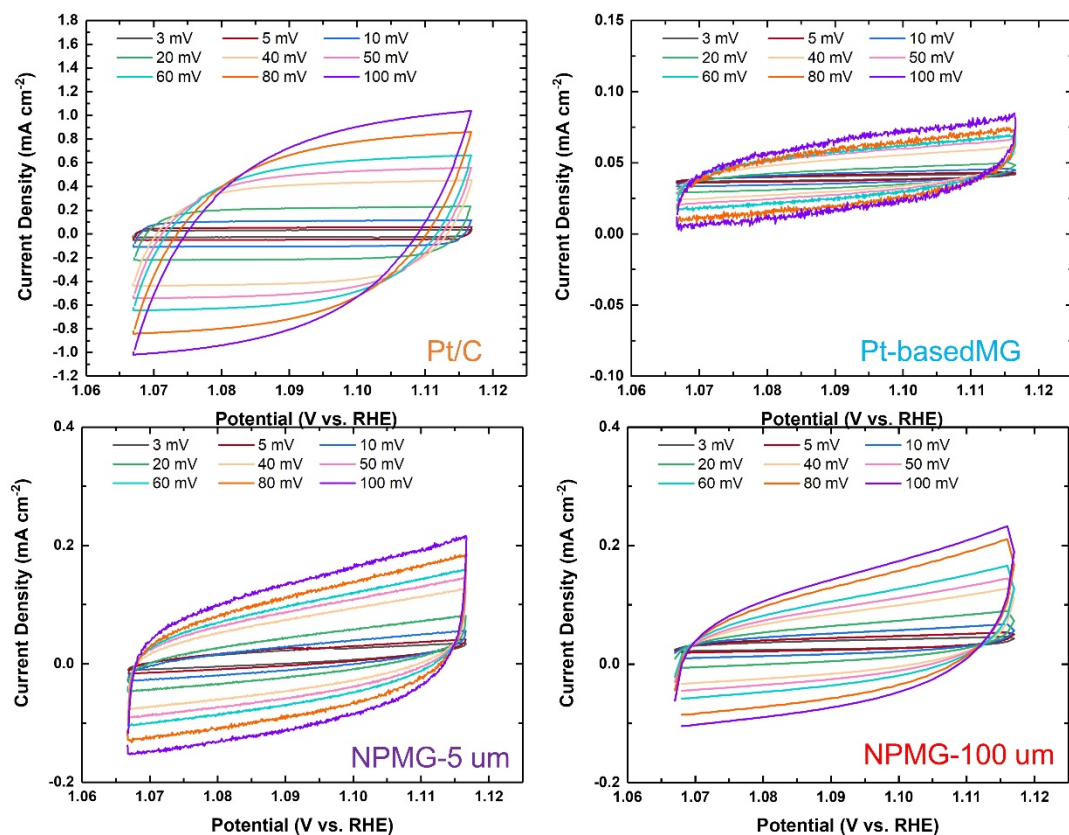


Fig. S8 (a) CV curves in 0.1 M KOH solution showing the double layer capacitance without electrochemical reactions (a-c). The difference in current density ($\Delta J = J_a - J_c$) at 0.05 V (vs. Ag/AgCl) plotted against scan rate and fitted to a linear regression for the estimation of capacitance.

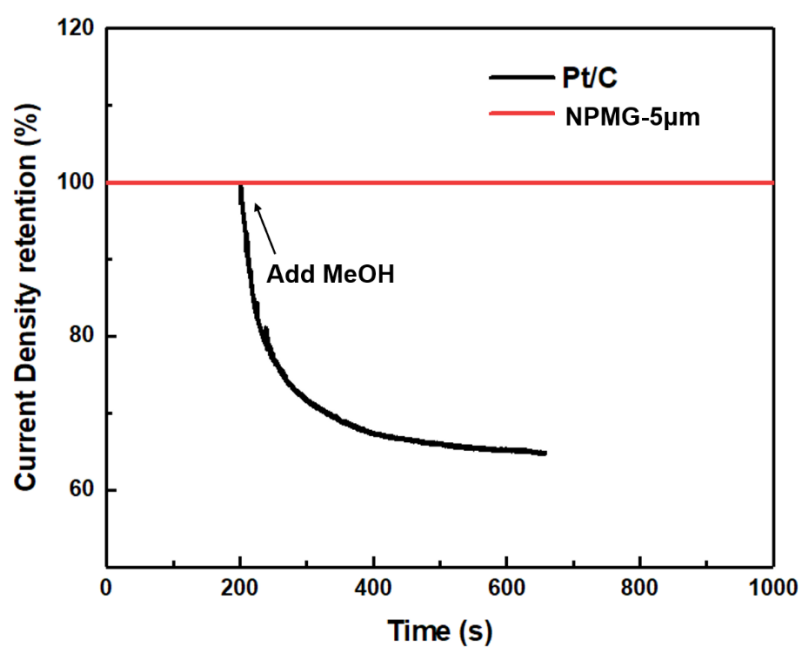


Fig. S9 (a) Chronoamperometric responses of NPMG and the benchmark Pt/C at 0.8 V in O₂-saturated 0.1 M KOH before and after addition of 2 M methanol under 1600 rpm.

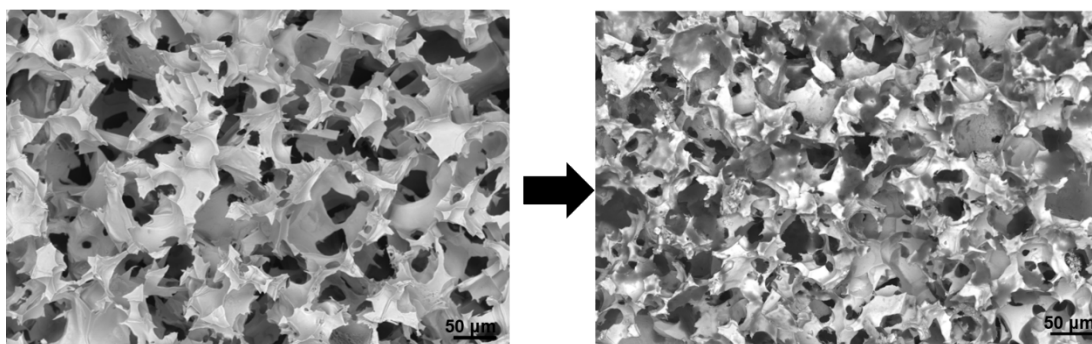


Fig. S10 the SEM analysis is performed to detect the surface structure of the sample after a long-time stability test.

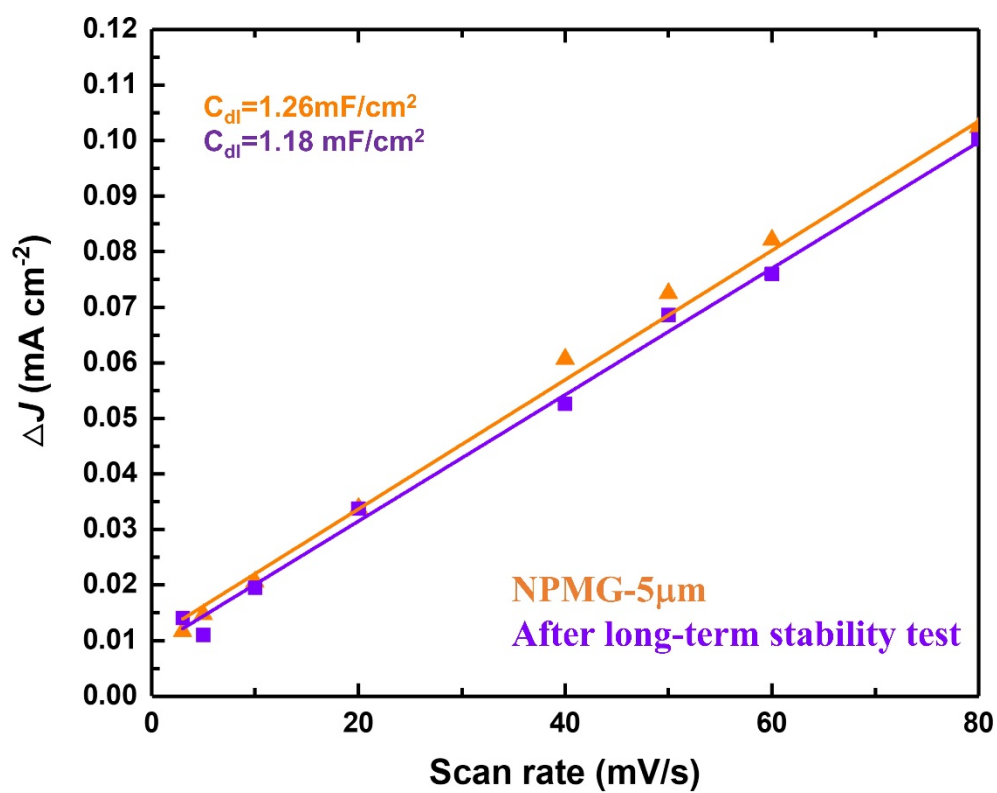


Fig. S11 Comparison of ECSA of samples before and after a long-time stability test.

Table S1. Comparison of Half-peak potential, Tafel slope and Stability for the ORR materials.

Catalysts	Half-peak potential mV vs. RHE	Tafel slope (mVdec ⁻¹)	Stability (%)	Electrolyte	References
NPMG-5 μ m.	835	54	100	0.1 M KOH	This work
NPMG-100 μ m	726	67	/	0.1 M KOH	
20% Pt/C	823	72	75	0.1 M KOH	
CoFe-N-C	897	67.7	88	0.1 M KOH	1
FeCo-N-HCN	860	52.1	90	0.1 M KOH	2
CoFe/N-GCT	790	76	75	0.1 M KOH	3
A-FeCo@NCNs	870	80	84	0.1 M KOH	4
CoFePPy	840	81.8	81	0.1 M KOH	5
CoFe-NC	940	68	75	0.1 M KOH	6
CoFe/SN-C	843	98	46.1	0.1 M KOH	7
NiFe-NC	850	140	86.3	0.1 M KOH	8
NPSC-Co ₂ Fe1	850		70.9	0.1 M KOH	9
CoNi-SAs/NC	760	58.7	80	0.1 M KOH	10
Fe, Mn-N/C900	904	35	93	0.1 M KOH	11
FeCo-N-rGO	850	70	60	0.1 M KOH	12
(Fe,Co)@NGC	850	78	91	0.1 M KOH	13
Ni-N ₄ /GHSs/Fe-N ₄	830	55	68.6	0.1 M KOH	14
NCAG/FeCo	890	64	89	0.1 M KOH	15
Pt/CaMnO ₃	950	65	84	0.1 M KOH	16
Co ₃ O ₄ /rGO	890	101	37	0.1 M KOH	17
Co ₃ O ₄ /N/C	920	/	28	0.1 M KOH	18
Co@Co ₃ O ₄ /NCNT	820	83	31	0.1 M KOH	19
Fe ₃ O ₄ /N/C	920	/	25	0.1 M KOH	20
Fe-N-DSC	840	/	78	0.1 M KOH	21
FeCo@N-GCNT-FD	880	/	43	0.1 M KOH	22
Co@h-ZIF	906	128	/	0.1 M KOH	23
PtCu nanoparticles	915	87	21	0.1MHClO ₄	24
Tin Selenide (SnSe)	750	137.5	/	0.1 M KOH	25
Co ₃ W ₃ C/NPG	790	/	/	0.1MHClO ₄	26
DS-Pd NPs	892	/	/	.1 M KOH	27
Co-N-C-MT/EA	810	77	13	0.1 M KOH	28
Fe-N-GO-400	820	60	85	0.1 M KOH	29
Fe-SA/HPC	910	68.7	/	0.1 M KOH	30
ZrO ₂ /NC	815	/	/	0.1 M KOH	31
WS ₂ /AC	860	68	96.4	N ₂ -aturated	32
WS ₂ /rGO	820	71	95.6	0.1 M KOH	32

Table S2. XPS element binding energy peak.

Sample	Before <i>J</i> -t	After <i>J</i> -t
BE (eV)		
Pt4f7 Scan A (Pt ⁰)	71.38	71.61
Pt4f5 Scan A (Pt ⁰)	74.58	74.20
Pt4f7 Scan B (Pt ²⁺)	72.68	72.61
Pt4f5 Scan B (Pt ²⁺)	76.08	76.00
Pt4f7 Scan C (Pt ⁴⁺)	/	74.90
Pt4f5 Scan C (Pt ⁴⁺)	/	77.80

Table S3. XPS Cu element binding energy peak

Sample	Before <i>J</i> -t	After <i>J</i> -t
BE (eV)		
Cu2p Scan A (Cu ⁰)	951.68	/
Cu2p Scan A (Cu ⁰)	932.08	/
Cu2p Scan B (Cu ²⁺)	953.62	951.78
Cu2p Scan B (Cu ²⁺)	933.88	933.08

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